

Notice of References Cited	Application/Control No. 10/691,392	Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner Phillip Nguyen	Art Unit 2828	Page 1 of 1

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*	C	US-6,381,047	04-2002	Frigo et al.	398/79
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NON-PATENT DOCUMENTS

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